MAX14811

# Dual, Unipolar/Bipolar, High-Voltage Digital Pulsers with Fault Condition Management 

General Description
The MAX14811 integrated circuit generates high-voltage, high-frequency unipolar or bipolar pulses from low-voltage logic inputs. The dual pulser features independent logic inputs, independent high-voltage pulser outputs with active clamps, and independent high-voltage supply inputs.

The device features fault condition management to protect the outputs. The outputs enter three-state if both $I N P_{-}$and $I N N_{-}$are logic-high. The device has a $9 \Omega$ output impedance for the high-voltage outputs and a $27 \Omega$ impedance for the active clamp. The high-voltage outputs are guaranteed to provide 2.0A (typ) output current. All the pulser outputs and clamp outputs have overvoltage protection.
The device uses three logic inputs per channel to control the positive and negative pulses and active clamp. Also included are two independent enable inputs. Disabling EN_ ensures the output MOSFETs are not accidentally turned on during fast power-supply ramping. This allows for faster ramp times and shorter delays between pulsing modes. A low-power shutdown mode reduces power consumption to less than $1 \mu \mathrm{~A}$. All digital inputs are CMOS compatible.
The device is available in a $7 \mathrm{~mm} \times 7 \mathrm{~mm}, 56$-pin TQFN exposed-pad package, and is specified over the $0^{\circ} \mathrm{C}$ to $+70^{\circ} \mathrm{C}$ commercial temperature range.

Features

## - Fault Condition Management <br> - Highly Integrated, High-Voltage, High-Frequency Unipolar/Bipolar Pulser <br> - $9 \Omega$ Output Impedance and 2.0A (typ) Output Current <br> - $27 \Omega$ Active Clamp <br> - Pulser and Clamp Overvoltage Protection <br> - 0 to +220 V Unipolar or $\pm 110 \mathrm{~V}$ Bipolar Outputs <br> - Matched Rise/Fall Times and Matched Propagation Delays <br> - CMOS-Compatible Logic Inputs <br> - $7 \mathrm{~mm} \times 7 \mathrm{~mm}$, 56-Pin TQFN Package <br> Applications

Ultrasound Medical Imaging
Cleaning Equipment
Industrial Imaging/Flaw Detection
Piezoelectric Drivers
Test Equipment

## Ordering Information appears at end of data sheet.

# Dual, Unipolar/Bipolar, High-Voltage Digital Pulsers with Fault Condition Management 

## ABSOLUTE MAXIMUM RATINGS

| oltages referenced to GND.) |  |
| :---: | :---: |
| $V_{\text {DD }}$ Logic Supply Voltage Range | -0.3V to +7 V |
| VCC_ Output Driver Positive |  |
| Supply Voltage Range | $-0.3 V$ to +15 V |
| $\mathrm{V}_{\text {EE_ }}$ Output Driver Negative |  |
| Supply Voltage Range | 15V to +0.3 V |
| VPP High Positive Supply Voltage Range ........ -0.3 V to +230V |  |
| $\mathrm{V}_{\mathrm{NN}}$ _ High Negative Supply Voltage Range...... -230 V to +0.3 V $\mathrm{V}_{\text {SS }}$ Voltage Range ................................. (VPP_-230V) to $\mathrm{V}_{\mathrm{NN}}$ |  |
|  |  |
| $V_{P P 1}-V_{N N 1}, V_{P P 2}-V_{N N 2}$ Supply |  |
| INP_, INN_, INC_, EN_, $\overline{\text { SHDN }}$ |  |
| Logic Input Range .................................. -0.3V to (VDD +0.3 V ) |  |



Note 1: This specification is based on the thermal characteristic of the package, the maximum junction temperature, and the setup described by JESD51. The maximum power dissipation for the MAX14811 might be limited by the thermal protection included in the device.
Warning: The MAX14811 is designed to operate with high voltages. Exercise caution.

## PACKAGE THERMAL CHARACTERISTICS (Note 2)

TQFN

$$
\begin{aligned}
& \text { Junction-to-Ambient Thermal Resistance }\left(\theta_{\mathrm{JA}}\right) \ldots . . . . . . .25^{\circ} \mathrm{C} / \mathrm{W} \\
& \text { Junction-to-Case Thermal Resistance }\left(\theta_{\mathrm{JC}}\right) \ldots . . . . . . . . .0 .8^{\circ} \mathrm{C} / \mathrm{W}
\end{aligned}
$$

Note 2: Package thermal resistances were obtained using the method described in JEDEC specification JESD51-7, using a fourlayer board. For detailed information on package thermal considerations, refer to www.maxim-ic.com/thermal-tutorial.
Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

## ELECTRICAL CHARACTERISTICS*

$\left(\mathrm{V}_{\mathrm{DD}}=+2.7 \mathrm{~V}\right.$ to $+6 \mathrm{~V}, \mathrm{~V}_{\mathrm{CC}_{-}}=+4.75 \mathrm{~V}$ to $+12.6 \mathrm{~V}, \mathrm{~V}_{\mathrm{EE}_{-}}=-12.6 \mathrm{~V}$ to $-4.75 \mathrm{~V}, \mathrm{~V}_{\mathrm{NN}_{-}}=-200 \mathrm{~V}$ to $0, \mathrm{~V}_{\mathrm{PP}}=0$ to $\left(\mathrm{V}_{\mathrm{NN}}+200 \mathrm{~V}\right), \mathrm{V}_{\mathrm{SS}} \leq$ the lower of $\mathrm{V}_{\text {NN1 }}$ or $\mathrm{V}_{\mathrm{NN} 2}, \mathrm{~T}_{\mathrm{A}}=\mathrm{T}_{J}=\mathrm{T}_{\mathrm{MIN}}$ to $\mathrm{T}_{\mathrm{MAX}}$, unless otherwise noted. Typical values are at $\mathrm{T}_{\mathrm{A}}=+25^{\circ} \mathrm{C}$.) (Note 3)

| PARAMETER | SYMBOL | CONDITIONS | MIN | TYP | MAX | UNITS |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| POWER SUPPLY ( $\mathbf{V}_{\text {DD }}, \mathrm{V}_{\mathrm{CC}_{-},}, \mathrm{V}_{\text {EE, }}, \mathrm{V}_{\text {PP_}}, \mathrm{V}_{\text {NN }}$ ) |  |  |  |  |  |  |
| Logic Supply Voltage | $V_{\text {DD }}$ |  | +2.7 | +3 | +6 | V |
| Positive Drive Supply Voltage | $\mathrm{V}_{\text {CC_ }}$ |  | +4.75 | +12 | +12.6 | V |
| Negative Drive Supply Voltage | $\mathrm{V}_{\text {EE_ }}$ |  | -12.6 | -12 | -4.75 | V |
| High-Side Supply Voltage | $\mathrm{V}_{\text {PP_ }}$ |  | 0 |  | $\begin{gathered} V_{N N_{-}}+ \\ 220 \end{gathered}$ | V |
| Low-Side Supply Voltage | $\mathrm{V}_{\mathrm{NN}}$ |  | -200 |  | 0 | V |
| $\mathrm{V}_{\text {PP_ }}-\mathrm{V}_{\text {NN_ }}$ |  |  | 0 |  | +220 | V |
| SUPPLY CURRENT (SINGLE CHANNEL) |  |  |  |  |  |  |
| V ${ }_{\text {DD }}$ Supply Current | IDD | $\mathrm{V}_{\text {IINN }} / V_{\text {INP }}=0 \mathrm{~V}, \mathrm{~V}_{\text {SHDN }}=0 \mathrm{~V}$ |  |  | 1 | $\mu \mathrm{A}$ |
|  |  | $\begin{aligned} & V_{E N_{-}}=V_{D D}, V_{\text {SHDN }}=V_{D D}, V_{I N C_{-}}=0 V \text { or } \\ & V_{D D}, V_{I N N_{-}}=V_{I N P_{-}, f} f=5 \mathrm{MHz} \end{aligned}$ |  | 100 | 200 | $\mu \mathrm{A}$ |

MAX14811

## Dual, Unipolar/Bipolar, High-Voltage Digital Pulsers with Fault Condition Management

## ELECTRICAL CHARACTERISTICS* (continued)

$\left(\mathrm{V}_{\mathrm{DD}}=+2.7 \mathrm{~V}\right.$ to $+6 \mathrm{~V}, \mathrm{~V}_{\mathrm{CC}}=+4.75 \mathrm{~V}$ to $+12.6 \mathrm{~V}, \mathrm{~V}_{\mathrm{EE}_{-}}=-12.6 \mathrm{~V}$ to $-4.75 \mathrm{~V}, \mathrm{~V}_{\mathrm{NN}_{-}}=-200 \mathrm{~V}$ to $0, \mathrm{~V}_{\mathrm{PP}}=0$ to $\left(\mathrm{V}_{\mathrm{NN}}+200 \mathrm{~V}\right)$, $\mathrm{V}_{\mathrm{SS}} \leq$ the lower of $\mathrm{V}_{\mathrm{NN} 1}$ or $\mathrm{V}_{\mathrm{NN} 2}, \mathrm{~T}_{\mathrm{A}}=\mathrm{T}_{\mathrm{J}}=\mathrm{T}_{\mathrm{MIN}}$ to $\mathrm{T}_{\mathrm{MAX}}$, unless otherwise noted. Typical values are at $\mathrm{T}_{\mathrm{A}}=+25^{\circ} \mathrm{C}$.) (Note 3)

| PARAMETER | SYMBOL | CONDITIONS | MIN | TYP | MAX | UNITS |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| V ${ }_{\text {CC__ }}$ Supply Current | ${ }^{\text {I CC_ }}$ | $V_{\text {SHDN }}=0 \mathrm{~V}, \mathrm{CH} 1$ and CH 2 |  |  | 1 | mA |
|  |  | $\mathrm{V}_{\mathrm{EN}}=\mathrm{V}_{\mathrm{DD}}, \mathrm{V}_{\text {SHDN }}=\mathrm{V}_{\mathrm{DD}}, \mathrm{CH} 1$ and CH 2 |  | 130 | 200 |  |
|  |  | $V_{E N_{-}}=V_{D D}, V_{\text {SHDN }}=V_{D D}, V_{I N C_{-}}=0 \mathrm{~V}$ or <br> $V_{D D}, V_{\text {INN_ }}=V_{\text {INP_ }}, f=5 \mathrm{MHz}, V_{C_{C-}}=5 \mathrm{~V}$, <br> $V_{D D}=3 \mathrm{~V}$, only one channel switching |  | 15 |  |  |
|  |  | $V_{E N_{-}}=V_{D D}, V_{\overline{S H D N}}=V_{D D}, V_{I N C_{-}}=0 V$ or $\mathrm{V}_{\mathrm{DD}}, \mathrm{V}_{\text {INN_ }}=\mathrm{V}_{\text {INP_ }}, f=5 \mathrm{MHz}, \mathrm{V}_{\mathrm{CC}}=$ $12 \mathrm{~V}, \mathrm{~V}_{\mathrm{DD}}=3 \mathrm{~V}$, only one channel switching |  | 36 |  |  |
| VEE_Supply Current | $\mathrm{IEE}_{-}$ | $V_{\text {SHDN }}=0 \mathrm{~V}, \mathrm{CH} 1$ and CH 2 |  |  | 1 | $\mu \mathrm{A}$ |
|  |  | $\mathrm{V}_{\mathrm{EN}}=\mathrm{V}_{\mathrm{DD}}, \mathrm{V}_{\text {SHDN }}=\mathrm{V}_{\mathrm{DD}}, \mathrm{CH} 1$ and CH 2 |  |  | 25 |  |
|  |  | $V_{E N_{-}}=V_{D D}, V_{\overline{S H D N}}=V_{D D}, V_{I N C_{-}}=0 V$ or $V_{D D}, V_{I N N_{-}}=V_{I N P_{-}} f=5 M H z, V_{E E_{-}}=-5 \mathrm{~V}$, only one channel switching |  |  | 200 |  |
|  |  | $V_{E N_{-}}=V_{D D}, V_{\overline{S H D N}}=V_{D D}, V_{I N C_{-}}=0 V$ or $V_{D D}, V_{I N N_{-}}=V_{\text {INP_, }} f=5 M H z, V_{E E_{-}}=-12 \mathrm{~V}$, only one channel switching |  |  | 200 |  |
| VPP_Supply Current | IPP_ | $V_{\text {SHDN }}=0 \mathrm{~V}, \mathrm{CH} 1$ and CH 2 |  |  | 1 | $\mu \mathrm{A}$ |
|  |  | $\mathrm{V}_{\mathrm{EN}}=\mathrm{V}_{\mathrm{DD}}, \mathrm{V}_{\text {SHDN }}=\mathrm{V}_{\mathrm{DD}}, \mathrm{CH} 1$ and CH 2 |  | 90 | 160 |  |
|  |  | $V_{E N_{-}}=V_{D D}, V_{\overline{S H D N}}=V_{D D}, V_{\text {INC_ }}=0 V$ or <br> $V_{D D}, V_{I N N_{-}}=V_{\text {INP }}, f=5 \mathrm{MHz}, V_{\text {PP_ }}=+5 \mathrm{~V}$, <br> $V_{N N_{-}}=-5 \overline{\mathrm{~V}}$, no load, only one channel switching |  | 9 |  | mA |
|  |  | $V_{E N_{-}}=V_{D D}, V_{\overline{S H D N}}=V_{D D}, V_{I N C_{-}}=0 V$ or $\mathrm{V}_{\mathrm{DD}}, \mathrm{V}_{\mathrm{PP}}=+80 \mathrm{~V}, \mathrm{~V}_{\mathrm{NN}}=-80 \mathrm{~V}$, pulse repetition frequency (PRF) $=10 \mathrm{kHz}, \mathrm{f}=$ 10 MHz , four periods, no load, only one channel switching |  | 0.6 |  |  |
| $\mathrm{V}_{\text {NN_ }}$ Supply Current | ${ }^{\text {INN_}}$ | $V_{\text {SHDN }}=0 \mathrm{~V}, \mathrm{CH} 1$ and CH 2 |  |  | 1 | $\mu \mathrm{A}$ |
|  |  | $\mathrm{V}_{\mathrm{EN}}=\mathrm{V}_{\mathrm{DD}}, \mathrm{V}_{\text {SHDN }}=\mathrm{V}_{\mathrm{DD}}, \mathrm{CH} 1$ and CH 2 |  | 40 | 80 |  |
|  |  | $V_{E N_{-}}=V_{D D}, V_{S H D N}=V_{D D}, V_{I N C_{-}}=0 V \text { or }$ <br> $V_{D D}, V_{I N N_{-}}=V_{I N P_{-}, f}=5 \mathrm{MHz}, V_{P_{P-}}=+5 \mathrm{~V}$, <br> $V_{\text {NN_ }}=-5 \overline{\mathrm{~V}}$, no load, only one channel switching |  | 9 |  | mA |
|  |  | $V_{E N_{-}}=V_{D D}, V_{\overline{S H D N}}=V_{D D}, V_{I N C_{-}}=0 V$ or $\mathrm{V}_{\mathrm{DD}}, \mathrm{V}_{\mathrm{PP}}=+80 \mathrm{~V}, \mathrm{~V}_{\mathrm{NN}}=-80 \mathrm{~V}$, pulse repetition frequency (PRF) $=10 \mathrm{kHz}, \mathrm{f}=$ 10 MHz , four periods, no load, only one channel switching |  | 0.6 |  |  |

MAX14811

## Dual, Unipolar/Bipolar, High-Voltage Digital Pulsers with Fault Condition Management

## ELECTRICAL CHARACTERISTICS* (continued)

$\left(\mathrm{V}_{\mathrm{DD}}=+2.7 \mathrm{~V}\right.$ to $+6 \mathrm{~V}, \mathrm{~V}_{\mathrm{CC}}=+4.75 \mathrm{~V}$ to $+12.6 \mathrm{~V}, \mathrm{~V}_{\mathrm{EE}_{-}}=-12.6 \mathrm{~V}$ to $-4.75 \mathrm{~V}, \mathrm{~V}_{\mathrm{NN}}=-200 \mathrm{~V}$ to $0, \mathrm{~V}_{\mathrm{PP}}=0$ to $\left(\mathrm{V}_{\mathrm{NN}}+200 \mathrm{~V}\right)$, $\mathrm{V}_{\mathrm{SS}} \leq$ the lower of $\mathrm{V}_{\text {NN1 }}$ or $\mathrm{V}_{\mathrm{NN} 2}, \mathrm{~T}_{\mathrm{A}}=\mathrm{T}_{J}=\mathrm{T}_{\text {MIN }}$ to $\mathrm{T}_{\mathrm{MAX}}$, unless otherwise noted. Typical values are at $\mathrm{T}_{\mathrm{A}}=+25^{\circ} \mathrm{C}$.) (Note 3)

| PARAMETER | SYMBOL | CONDITIONS | MIN | TYP | MAX | UNITS |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| LOGIC INPUTS (EN_, $\overline{\text { SHDN, }}$, INN_, INP_, INC_) |  |  |  |  |  |  |
| Low-Level Input Voltage | VIL |  |  |  | $\begin{gathered} 0.25 x \\ V_{D D} \end{gathered}$ | V |
| High-Level Input Voltage | $\mathrm{V}_{\mathrm{IH}}$ |  | $\begin{gathered} 0.75 x \\ V_{D D} \\ \hline \end{gathered}$ |  |  | V |
| Logic-Input Capacitance | $\mathrm{CIN}^{\text {I }}$ |  |  | 5 |  | pF |
| Logic-Input Leakage (INC_, $\overline{S H D N}, E N \_$Only) | IIN | $V_{I N}=0 V$ or $V_{D D}$ | -1 |  | +1 | $\mu \mathrm{A}$ |
| Pulldown Resistor (INN_, INP_ Only) | RPIN |  | 7 | 10 | 13 | $\mathrm{k} \Omega$ |
| OUTPUT (OUT_) |  |  |  |  |  |  |
| OUT_ Output-Voltage Range | Vout_ | No load at OUT_ | $\mathrm{V}_{\text {NN }}$ |  | $\mathrm{V}_{\text {PP_ }}$ | V |
|  |  | 100mA load | $\begin{gathered} \mathrm{V}_{\mathrm{NN},-}+ \\ 2.5 \end{gathered}$ |  | $\begin{gathered} \hline \mathrm{V}_{\text {PP_ }}- \\ 2.5 \end{gathered}$ |  |
| Low-Side Small-Signal Output Impedance | RSOL | $\mathrm{I}_{\mathrm{ON}}=-100 \mathrm{~mA}, \mathrm{~V}_{\mathrm{CC}_{-}}=+12 \mathrm{~V} \pm 5 \% \text {, }$ DC-coupled |  | 9 | 17 | $\Omega$ |
|  |  | $\mathrm{ION}_{-}=-100 \mathrm{~mA}, \mathrm{~V}_{\mathrm{CC}_{-}}=+5 \mathrm{~V} \pm 5 \%,$ DC-coupled |  | 9.5 | 18 |  |
| High-Side Small-Signal Output Impedance | $\mathrm{R}_{\mathrm{HOS}}$ | $\mathrm{I}_{\mathrm{OP}}=-100 \mathrm{~mA}, \mathrm{~V}_{\mathrm{CC}_{-}}=+12 \mathrm{~V} \pm 5 \%,$ DC-coupled |  | 10.5 | 17 | $\Omega$ |
|  |  | $\mathrm{l}_{\mathrm{OP}}=-100 \mathrm{~mA}, \mathrm{~V}_{\mathrm{CC}_{-}}=+5 \mathrm{~V} \pm 5 \%,$ DC-coupled |  | 12 | 18 |  |
| Low-Side Output Current | $\mathrm{IOL}^{\text {O }}$ | $\mathrm{V}_{\text {CC_ }}=+12 \mathrm{~V} \pm 5 \%, \mathrm{~V}_{\text {OUT- }}-\mathrm{V}_{\text {NN_ }}=100 \mathrm{~V}$ | 1.3 | 2.5 |  | A |
| High-Side Output Current | ${ }^{\mathrm{OH}}$ | $\mathrm{V}_{\text {CC_ }}=+12 \mathrm{~V} \pm 5 \%$, $\mathrm{V}_{\text {OUT }}-\mathrm{V}_{\text {PP_ }}=100 \mathrm{~V}$ | 1.3 | 2 |  | A |
| Off-Output Capacitance | $\mathrm{C}_{\text {O(OFF) }}$ | OP_, ON_, OCP_ and OCN_ connected together, $\mathrm{V}_{\text {PP_ }}=+100 \mathrm{~V}, \mathrm{~V}_{\text {NN_ }}=-100 \mathrm{~V}$ |  | 45 |  | pF |
| Off-Output Leakage Current | ILK | $\begin{array}{\|l} \mathrm{V}_{\text {PP }}=+100 \mathrm{~V}, \mathrm{~V}_{\text {NN }}=-100 \mathrm{~V}, \mathrm{~V}_{\mathrm{EN}_{-}}=0 \mathrm{~V}, \\ \mathrm{~V}_{\text {OUT }}=-100 \mathrm{~V} \text { to }+100 \mathrm{~V} \\ \hline \end{array}$ | -1 |  | +1 | $\mu \mathrm{A}$ |
| Low-Side Signal-Clamp Output Impedance | $\mathrm{R}_{\text {CLS }}$ | $\mathrm{I}_{\mathrm{OCN}}=-100 \mathrm{~mA}$, DC-coupled, $\mathrm{V}_{\mathrm{CC}_{-}}=+12 \mathrm{~V} \pm 5 \%, \mathrm{~V}_{\mathrm{EE}_{-}}=-\mathrm{V}_{\mathrm{CC}_{-}}$ |  | 22 | 50 | $\Omega$ |
|  |  | $\mathrm{I}_{\mathrm{OCN}}=-100 \mathrm{~mA}$, DC-coupled, $\mathrm{V}_{\mathrm{CC}_{-}}=+5 \mathrm{~V} \pm 5 \%, \mathrm{~V}_{\mathrm{EE}_{-}}=-\mathrm{V}_{\mathrm{CC}_{-}}$ |  | 24 | 65 |  |
| High-Side Signal-Clamp Output Impedance | $\mathrm{R}_{\mathrm{CHS}}$ | $\begin{array}{\|l\|} \hline \mathrm{l}_{\mathrm{OCP}}^{-} \end{array}=-100 \mathrm{~mA}, \mathrm{DC}-\text { coupled, }, ~=~+12 \mathrm{~V} \pm 5 \%, \mathrm{~V}_{\mathrm{EE}_{-}}=-\mathrm{V}_{\mathrm{CC}_{-}} .$ |  | 28 | 50 | $\Omega$ |
|  |  | IOCP_ $=-100 \mathrm{~mA}$, DC-coupled, $\mathrm{V}_{\mathrm{CC}_{-}}^{-}=+5 \mathrm{~V} \pm 5 \%, \mathrm{~V}_{\mathrm{EE}_{-}}=-\mathrm{V}_{\mathrm{CC}_{-}}$ |  | 38 | 65 |  |
| Low-Side Gate Short Impedance | RLSH | $\begin{aligned} & \mathrm{V}_{\mathrm{CC}_{-}}=+12 \mathrm{~V} \pm 5 \%, \mathrm{~V}_{\mathrm{EE}_{-}}=-\mathrm{V}_{\mathrm{CC}_{-}}, \\ & \mathrm{I}_{\mathrm{CGN}}=10 \mathrm{~mA}, \mathrm{~V}_{\mathrm{EN}}=0 \mathrm{OV} \\ & \hline \end{aligned}$ |  |  | 100 | $\Omega$ |
|  |  | $\begin{aligned} & \mathrm{V}_{\mathrm{CC}_{-}}=+12 \mathrm{~V} \pm 5 \%, \mathrm{~V}_{\mathrm{EE}_{-}}=-\mathrm{V}_{\mathrm{CC}_{-}}, \\ & \mathrm{I}_{\mathrm{CGN}}=10 \mathrm{~mA}, \mathrm{~V}_{\mathrm{EN}}=\mathrm{V}_{\mathrm{DD}} \\ & \hline \end{aligned}$ | 5 | 7.5 | 10 | $\mathrm{k} \Omega$ |

# Dual, Unipolar/Bipolar, High-Voltage Digital Pulsers with Fault Condition Management 

## ELECTRICAL CHARACTERISTICS* (continued)

$\left(\mathrm{V}_{\mathrm{DD}}=+2.7 \mathrm{~V}\right.$ to $+6 \mathrm{~V}, \mathrm{~V}_{\mathrm{CC}}=+4.75 \mathrm{~V}$ to $+12.6 \mathrm{~V}, \mathrm{~V}_{\mathrm{EE}_{-}}=-12.6 \mathrm{~V}$ to $-4.75 \mathrm{~V}, \mathrm{~V}_{\mathrm{NN}_{-}}=-200 \mathrm{~V}$ to $0, \mathrm{~V}_{\mathrm{PP}}=0$ to $\left(\mathrm{V}_{\mathrm{NN}}+200 \mathrm{~V}\right), \mathrm{V}_{\mathrm{SS}} \leq$ the lower of $\mathrm{V}_{\mathrm{NN} 1}$ or $\mathrm{V}_{\mathrm{NN} 2}, \mathrm{~T}_{\mathrm{A}}=\mathrm{T}_{\mathrm{J}}=\mathrm{T}_{\mathrm{MIN}}$ to $\mathrm{T}_{\mathrm{MAX}}$, unless otherwise noted. Typical values are at $\mathrm{T}_{\mathrm{A}}=+25^{\circ} \mathrm{C}$.) (Note 3)

| PARAMETER | SYMBOL | CONDITIONS | MIN | TYP | MAX | UNITS |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| High-Side Gate Short Impedance | $\mathrm{R}_{\mathrm{HSH}}$ | $\begin{aligned} & \mathrm{V}_{\mathrm{CC}_{-}}=+12 \mathrm{~V} \pm 5 \%, \mathrm{~V}_{\mathrm{EE}_{-}}=-\mathrm{V}_{\mathrm{CC}_{-}} \\ & \mathrm{I}_{\mathrm{CGP}}^{-}=10 \mathrm{~mA}, \mathrm{~V}_{\mathrm{EN}}=0 \mathrm{OV} \end{aligned}$ |  |  | 100 | $\Omega$ |
|  |  | $\begin{aligned} & \mathrm{V}_{\mathrm{CC}_{-}}=+12 \mathrm{~V} \pm 5 \%, \mathrm{~V}_{\mathrm{EE}_{-}}=-\mathrm{V}_{\mathrm{CC}_{-}} \\ & \mathrm{I}_{\mathrm{CGP}}^{-}=10 \mathrm{~mA}, \mathrm{~V}_{\mathrm{EN}}=\mathrm{V}_{\mathrm{DD}} \end{aligned}$ | 5 | 7.5 | 10 | k $\Omega$ |
| THERMAL SHUTDOWN |  |  |  |  |  |  |
| Thermal Shutdown | THDN | Junction temperature rising |  | 150 |  | ${ }^{\circ} \mathrm{C}$ |
| Thermal-Shutdown Hysteresis |  |  |  | 20 |  | ${ }^{\circ} \mathrm{C}$ |
| DYNAMIC CHARACTERISTICS ( $\mathrm{R}_{\mathrm{L}}=100 \Omega$, $\mathrm{C}_{\mathrm{L}}=100 \mathrm{pF}$, unless otherwise noted.) |  |  |  |  |  |  |
| Logic Input to Output Rise Propagation Delay | tPLH | $\mathrm{V}_{\mathrm{CC}_{-}}=+12 \mathrm{~V}, \mathrm{~V}_{\mathrm{PP}_{-}}=+5 \mathrm{~V}, \mathrm{~V}_{\mathrm{NN}}=-5 \mathrm{~V},$ <br> Figure 1 |  | 15 |  | ns |
| Logic Input to Output Fall Propagation Delay | tPHL | $\mathrm{V}_{\mathrm{CC}_{-}}=+12 \mathrm{~V}, \mathrm{~V}_{\mathrm{PP}_{-}}=+5 \mathrm{~V}, \mathrm{~V}_{\mathrm{NN}}=-5 \mathrm{~V},$ <br> Figure 1 |  | 15 |  | ns |
| Logic Input to Output Rise Propagation Delay | tPOH | $\mathrm{V}_{\mathrm{CC}_{-}}=+12 \mathrm{~V}, \mathrm{~V}_{\mathrm{PP}}^{-}=+5 \mathrm{~V}, \mathrm{~V}_{\mathrm{NN}}=-5 \mathrm{~V},$ <br> Figure 1 |  | 15 |  | ns |
| Logic Input to Output Fall Propagation Delay | tPOL | $\mathrm{V}_{C C_{-}}=+12 \mathrm{~V}, \mathrm{~V}_{\text {PP_ }}=+5 \mathrm{~V}, \mathrm{~V}_{\mathrm{NN}}=-5 \mathrm{~V},$ <br> Figure 1 |  | 15 |  | ns |
| Logic Input to Output Rise Propagation Delay Clamp | tPHO | $\mathrm{V}_{\mathrm{CC}_{-}}=+12 \mathrm{~V}, \mathrm{~V}_{\mathrm{PP}}^{-}=+5 \mathrm{~V}, \mathrm{~V}_{\mathrm{NN}_{-}}=-5 \mathrm{~V},$ <br> Figure 1 |  | 15 |  | ns |
| Logic Input to Output Fall Propagation Delay Clamp | tpLo | $\mathrm{V}_{\mathrm{CC}_{-}}=+12 \mathrm{~V}, \mathrm{~V}_{\mathrm{PP}}^{-}=+5 \mathrm{~V}, \mathrm{~V}_{\mathrm{NN}}=-5 \mathrm{~V},$ <br> Figure 1 |  | 15 |  | ns |
| OUT_ Rise Time (GND to VPP_) | $t_{\text {ROP }}$ | $\begin{aligned} & \mathrm{V}_{\mathrm{PP}}=+100 \mathrm{~V}, \mathrm{~V}_{\mathrm{NN}}=-100 \mathrm{~V}, \mathrm{~V}_{\mathrm{CC}_{-}}=+12 \mathrm{~V} \\ & \pm 5 \%, \mathrm{~V}_{\mathrm{EE}_{-}}=-\mathrm{V}_{\mathrm{CC}_{-},} \text {Figure } 1 \end{aligned}$ |  | 9 | 20 | ns |
| OUT_ Rise Time (VNN $\mathrm{V}_{\text {N }}$ to GND) | $\mathrm{t}_{\mathrm{RNO}}$ | $\begin{aligned} & \mathrm{V}_{\mathrm{PP}}=+100 \mathrm{~V}, \mathrm{~V}_{\mathrm{NN}_{-}}=-100 \mathrm{~V}, \mathrm{~V}_{\mathrm{CC}_{-}}=+12 \mathrm{~V} \\ & \pm 5 \%, \mathrm{~V}_{\mathrm{EE}_{-}}=-\mathrm{V}_{\mathrm{CC}_{-},} \text {Figure } 1 \end{aligned}$ |  | 17 | 35 | ns |
| OUT_ Rise Time ( $\mathrm{V}_{\mathrm{NN}}$ _ to $\mathrm{V}_{\text {PP_}}$ ) | $t_{\text {RNP }}$ | $\begin{aligned} & \mathrm{V}_{\mathrm{PP}}=+100 \mathrm{~V}, \mathrm{~V}_{\mathrm{NN}}=-100 \mathrm{~V}, \mathrm{~V}_{\mathrm{CC}_{-}}=+12 \mathrm{~V} \\ & \pm 5 \%, \mathrm{~V}_{\mathrm{EE}_{-}}=-\mathrm{V}_{\mathrm{CC}_{-}} \text {, Figure } 1 \end{aligned}$ |  | 10.5 | 35 | ns |
| OUT_ Fall Time (GND to $\mathrm{V}_{\text {NN_ }}$ ) | $\mathrm{t}_{\text {FON }}$ | $\begin{aligned} & \mathrm{V}_{\mathrm{PP}}=+100 \mathrm{~V}, \mathrm{~V}_{\text {NN }}=-100 \mathrm{~V}, \mathrm{~V}_{\mathrm{CC}_{-}}=+12 \mathrm{~V} \\ & \pm 5 \%, \mathrm{~V}_{\mathrm{EE}_{-}}=-\mathrm{V}_{\mathrm{CC}_{-},} \text {Figure } 1 \end{aligned}$ |  | 9 | 20 | ns |
| OUT_ Fall Time (VPP_ to GND) | $\mathrm{t}_{\text {FPO }}$ | $\begin{aligned} & \mathrm{V}_{\text {PP }}=+100 \mathrm{~V}, \mathrm{~V}_{\mathrm{NN}}=-100 \mathrm{~V}, \mathrm{~V}_{\mathrm{CC}_{-}}=+12 \mathrm{~V} \\ & \pm 5 \%, \mathrm{~V}_{\mathrm{EE}_{-}}=-\mathrm{V}_{\mathrm{CC}_{-}} \text {, Figure } 1 \end{aligned}$ |  | 17 | 35 | ns |
| OUT_ Fall Time ( $\mathrm{VPP}_{\text {P }}$ to $\mathrm{V}_{\mathrm{NN}}$ ) | $\mathrm{t}_{\text {FPN }}$ | $\begin{aligned} & \mathrm{V}_{\mathrm{PP}}=+100 \mathrm{~V}, \mathrm{~V}_{\mathrm{NN}_{-}}=-100 \mathrm{~V}, \mathrm{~V}_{\mathrm{CC}_{-}}=+12 \mathrm{~V} \\ & \pm 5 \%, \mathrm{~V}_{\mathrm{EE}_{-}}=-\mathrm{V}_{\mathrm{CC}_{-},} \text {Figure } 1 \end{aligned}$ |  | 10.5 | 35 | ns |
| OUT_ Enable Time from EN_ (Figure 2) | ten | $\mathrm{V}_{\mathrm{CC}_{-}}=+12 \mathrm{~V} \pm 5 \%, \mathrm{~V}_{\mathrm{EE}_{-}}=-\mathrm{V}_{\mathrm{CC}}$ |  |  | 100 | ns |
|  |  | $\mathrm{V}_{\text {CC_ }}=+5 \mathrm{~V} \pm 5 \%, \mathrm{~V}_{\mathrm{EE}_{-}}=-\mathrm{V}_{\mathrm{CC}}$ |  |  | 150 |  |
| OUT_ Disable Time from EN_ (Figure 2) | ${ }^{\text {D }}$ | $\mathrm{V}_{\mathrm{CC}_{-}}=+12 \mathrm{~V} \pm 5 \%, \mathrm{~V}_{\mathrm{EE}_{-}}=-\mathrm{V}_{\mathrm{CC}}$ |  |  | 100 | ns |
|  |  | $\mathrm{V}_{\text {CC_ }}=+5 \mathrm{~V} \pm 5 \%, \mathrm{~V}_{\mathrm{EE}_{-}}=-\mathrm{V}_{\text {CC_ }}$ |  |  | 150 |  |
| Clamp Enable Time from INC_ (Figure 3) | $t_{\text {EN-CL }}$ | $\mathrm{V}_{\mathrm{CC}_{-}}=+12 \mathrm{~V} \pm 5 \%, \mathrm{~V}_{\mathrm{EE}_{-}}=-\mathrm{V}_{\mathrm{CC}}$ |  |  | 100 | ns |
|  |  | $\mathrm{V}_{\text {CC_ }}=+5 \mathrm{~V} \pm 5 \%, \mathrm{~V}_{\mathrm{EE}_{-}}=-\mathrm{V}_{\text {CC_ }}$ |  |  | 150 |  |

MAX14811

## Dual, Unipolar/Bipolar, High-Voltage Digital Pulsers with Fault Condition Management

## ELECTRICAL CHARACTERISTICS* (continued)

$\left(\mathrm{V}_{\mathrm{DD}}=+2.7 \mathrm{~V}\right.$ to $+6 \mathrm{~V}, \mathrm{~V}_{\mathrm{CC}}=+4.75 \mathrm{~V}$ to $+12.6 \mathrm{~V}, \mathrm{~V}_{\mathrm{EE}_{-}}=-12.6 \mathrm{~V}$ to $-4.75 \mathrm{~V}, \mathrm{~V}_{\mathrm{NN}_{-}}=-200 \mathrm{~V}$ to $0, \mathrm{~V}_{\mathrm{PP}}=0$ to $\left(\mathrm{V}_{\mathrm{NN}}+200 \mathrm{~V}\right)$, $\mathrm{V}_{\mathrm{SS}} \leq$ the lower of $\mathrm{V}_{\mathrm{NN} 1}$ or $\mathrm{V}_{\mathrm{NN} 2}, \mathrm{~T}_{\mathrm{A}}=\mathrm{T}_{\mathrm{J}}=\mathrm{T}_{\mathrm{MIN}}$ to $\mathrm{T}_{\mathrm{MAX}}$, unless otherwise noted. Typical values are at $\mathrm{T}_{\mathrm{A}}=+25^{\circ} \mathrm{C}$.) (Note 3)

| PARAMETER | SYMBOL | CONDITIONS | MIN | TYP | MAX | UNITS |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| Clamp Disable Time from INC_ (Figure 3) | ${ }^{\text {t }}$ I-CL | $\mathrm{V}_{\mathrm{CC}_{-}}=+12 \mathrm{~V} \pm 5 \%, \mathrm{~V}_{\mathrm{EE}_{-}}=-\mathrm{V}_{\mathrm{CC}}$ |  |  | 100 | ns |
|  |  | $\mathrm{V}_{\mathrm{CC}_{-}}=+5 \mathrm{~V} \pm 5 \%, \mathrm{~V}_{\mathrm{EE}_{-}}=-\mathrm{V}_{\mathrm{CC}}$ |  |  | 150 |  |
| Short Enable Time from EN_ <br> (Figure 4) | ${ }_{\text {ten-SH }}$ | $\begin{aligned} & \mathrm{V}_{\mathrm{PP}_{-}}=+12 \mathrm{~V}, \mathrm{~V}_{\mathrm{NN}}=0 \mathrm{~V}, \\ & \mathrm{~V}_{\mathrm{CC}}=+12 \mathrm{~V} \pm 5 \%, \mathrm{~V}_{\mathrm{EE}_{-}}=-\mathrm{V}_{\mathrm{CC}}{ }^{2} \end{aligned}$ |  |  | 1000 | ns |
|  |  | $\begin{aligned} & \mathrm{V}_{\mathrm{PP}_{-}}=+5 \mathrm{~V}, \mathrm{~V}_{\mathrm{NN}}=0 \mathrm{~V}, \\ & \mathrm{~V}_{\mathrm{CC}_{-}}=+5 \mathrm{~V} \pm 5 \%, \mathrm{~V}_{\mathrm{EE}_{-}}=-\mathrm{V}_{\mathrm{CC}} \\ & \hline \end{aligned}$ |  |  | 1000 |  |
| Short Disable Time from EN_ <br> (Figure 4) | ${ }^{\text {tol-SH }}$ | $\begin{array}{\|l} \hline \mathrm{V}_{\text {PP_- }}=+12 \mathrm{~V}, \mathrm{~V}_{\mathrm{NN}}=0 \mathrm{~V}, \\ \mathrm{~V}_{\mathrm{CC}}=+12 \mathrm{~V} \pm 5 \%, \mathrm{~V}_{\mathrm{EE}_{-}}=-\mathrm{V}_{\mathrm{CC}} \\ \hline \end{array}$ |  |  | 250 | ns |
|  |  | $\begin{aligned} & \mathrm{V}_{\mathrm{PP}}^{-} \\ & =+5 \mathrm{~V}, \mathrm{~V}_{\mathrm{NN}}=0 \mathrm{~V}, \\ & \mathrm{~V}_{\mathrm{CC}}^{-} \end{aligned}=+5 \mathrm{~V} \pm 5 \%, \mathrm{~V}_{\mathrm{EE}_{-}}=-\mathrm{V}_{\mathrm{CC}}$ |  |  | 250 |  |
| INP_ to INN_ Fault Overlap Detection Time (Figure 5) | tov | $V_{D D}=+3.3 V \pm 5 \%$ | 2 |  |  | ns |
| Recovery Time from Fault Condition (Figure 6) | $t_{\text {REC }}$ | $\mathrm{V}_{\mathrm{DD}}=+3.3 \mathrm{~V}, \mathrm{~V}_{\text {CC_ }}=+12 \mathrm{~V} \pm 5 \%$ |  | 50 | 120 | ns |
| Crosstalk |  | $\begin{aligned} & V_{P P}=V_{C C_{-}}=+5 \mathrm{~V}, V_{\mathrm{NN}_{-}}=V_{\mathrm{EE}_{-}}=-5 \mathrm{~V}, \\ & f=5 \mathrm{MHz} \end{aligned}$ |  | 69 |  | dB |
| 2nd Harmonic Distortion | 2 HD | $\begin{aligned} & \mathrm{V}_{\text {PP }}=-\mathrm{V}_{\text {NN_ }}=100 \mathrm{~V}, \text { foUT }=5 \mathrm{MHz}, \\ & \mathrm{~V}_{\mathrm{CC}_{-}}=12 \mathrm{~V} \end{aligned}$ |  | -48 |  | dB |
| RMS Output Jitter | $\mathrm{t}_{J}$ | $\mathrm{V}_{\mathrm{CC}_{-}}=12 \mathrm{~V}$ |  | 9 |  | ps |

Note 3: All units are $100 \%$ production tested at $\mathrm{T}_{\mathrm{A}}=+70^{\circ} \mathrm{C}$. Specifications over operating temperature range are guaranteed by design.
$\qquad$

MAX14811

## Dual, Unipolar/Bipolar, High-Voltage Digital Pulsers with Fault Condition Management

Typical Operating Characteristics
$\left(\mathrm{V}_{\mathrm{DD}}=+3.3 \mathrm{~V}, \mathrm{~V}_{\mathrm{CC}_{-}}=+12 \mathrm{~V}, \mathrm{~V}_{\mathrm{EE}_{-}}=-12 \mathrm{~V}, \mathrm{~V}_{\mathrm{SS}}=-100 \mathrm{~V}, \mathrm{~V}_{\mathrm{PP}_{-}}=+100 \mathrm{~V}, \mathrm{~V}_{\mathrm{NN}}=-100 \mathrm{~V}, \mathrm{f}_{\mathrm{OUT}}=5 \mathrm{MHz}, \mathrm{T}_{\mathrm{A}}=+25^{\circ} \mathrm{C}\right.$, unless otherwise noted.)


Icc_vs. TEMPERATURE


Ipp_ vs. TEMPERATURE


Icc_vs. OUTPUT FREQUENCY


IPP vs. OUTPUT FREQUENCY


Ipp_ vs. TEMPERATURE


Icc_vs. TEMPERATURE


Ipp vs. OUTPUT FREQUENCY


InN_ vs. OUTPUT FREQUENCY


## Dual, Unipolar/Bipolar, High-Voltage Digital Pulsers with Fault Condition Management

Typical Operating Characteristics (continued)
$\left(\mathrm{V}_{\mathrm{DD}}=+3.3 \mathrm{~V}, \mathrm{~V}_{\mathrm{CC}_{-}}=+12 \mathrm{~V}, \mathrm{~V}_{\mathrm{EE}_{-}}=-12 \mathrm{~V}, \mathrm{~V}_{\mathrm{SS}}=-100 \mathrm{~V}, \mathrm{~V}_{\mathrm{PP}_{-}}=+100 \mathrm{~V}, \mathrm{~V}_{\mathrm{NN}_{-}}=-100 \mathrm{~V}, \mathrm{f}_{\mathrm{OU}} \mathrm{T}_{-}=5 \mathrm{MHz}, \mathrm{T}_{\mathrm{A}}=+25^{\circ} \mathrm{C}\right.$, unless otherwise noted.)

INN_ vs. OUTPUT FREQUENCY


OUT_ RISE TIME (GND TO VPP_) vs. Vcc_/Vee_ SUPPLY VOLTAGE


INP_-TO-OUT_ RISE PROPAGATION DELAY
vs. TEMPERATURE


Inn_ vs. TEMPERATURE


OUT_ FALL TIME (GND TO VnN_) vs. VCc_/Vee_SUPPLY VOLTAGE


INP_-TO-OUT_ FALL PROPAGATION DELAY vs. VCC /VEE SUPPLY VOLTAGE


InN_vs. TEMPERATURE


INP -TO-OUT RISE PROPAGATION DELAY vs. Vcc_Nee_SUPPLY VOLTAGE


INP_-TO-OUT_ FALL PROPAGATION DELAY vs. TEMPERATURE


## Dual, Unipolar/Bipolar, High-Voltage Digital Pulsers with Fault Condition Management

Pin Configuration


Pin Description

| PIN | NAME | FUNCTION |
| :---: | :---: | :--- |
| 1 | CGP1 | Channel 1 High-Side Gate Input. Connect a 1nF to 10nF capacitor between CDP1 and CGP1 as <br> close as possible to the device. |
| 2,3 | $V_{\text {PP1 }}$ | Channel 1 High-Side Positive Supply-Voltage Input. Bypass VPP1 to GND with a 0.1 1 F capacitor <br> as close as possible to the device. Depending on the pulser lead, additional bypassing may be <br> required (see the Power Supplies and Bypassing section). |
| $4,10,33,39$ | N.C. | No Connection. Not connected internally. |
| 5 | OP1 | Channel 1 High-Side Drain Output |
| 6 | OCP1 | Channel 1 High-Side Clamp Output |
| $7,15,28$, <br> $36,44,55$ | GND | Ground |
| 8 | OCN1 | Channel 1 Low-Side Clamp Output |
| 9 | ON1 | Channel 1 Low-Side Drain Output |
| 11,12 | VNN1 $^{2}$ | Channel 1 High-Side Negative Supply-Voltage Input. Bypass V VN1 to GND with a 0.1 <br> as close as papsible to the device. Depending on the pulser lead, additional bypassing may be <br> required (see the Power Supplies and Bypassing section). |

# Dual, Unipolar/Bipolar, High-Voltage Digital Pulsers with Fault Condition Management 

Pin Description (continued)

| PIN | NAME | FUNCTION |
| :---: | :---: | :---: |
| 13 | CGN1 | Channel 1 Low-Side Gate Input. Connect a 1nF to 10nF capacitor between CDN1 and CGN1 as close as possible to the device. |
| 14 | CDN1 | Channel 1 Low-Side Driver Output. Connect a 1nF to 10nF capacitor between CDN1 and CGN1 as close as possible to the device. |
| 16,54 | $\mathrm{V}_{\mathrm{CC} 1}$ | Channel 1 Gate-Drive Supply-Voltage Input. Bypass $\mathrm{V}_{\mathrm{CC} 1}$ to GND with a $0.1 \mu \mathrm{~F}$ capacitor as close as possible to the device. |
| 17 | INN1 | Channel 1 Low-Side Logic Input (Table 1). INN1 has a 10k $\Omega$ pulldown resistor. |
| 18 | INC1 | Channel 1 Clamp Logic Input. Clamps OCP1 and OCN1 are turned on when INC1 is high and when INP1 and INN1 are low and SHDN and EN1 are high (Table 1). |
| 19 | INP1 | Channel 1 High-Side Logic Input (Table 1). INP1 has a 10k pulldown resistor. |
| 20 | EN1 | Channel 1 Enable Logic Input. Drive EN1 high to enable OP1, ON1, OCN1, and OCP1. Pull EN1 Iow to turn on the gate-source short circuit (Table 1). |
| 21 | $\overline{\text { SHDN }}$ | Active-Low Shutdown Logic Input (Table 1) |
| 22 | AGND | Analog Ground. AGND must be connected to common GND. |
| 23 | EN2 | Channel 2 Enable Logic Input. Drive EN2 high to enable OP2, ON2, OCN2, and OCP2. Pull EN2 low to turn on the gate-source short circuit (Table 1). |
| 24 | INP2 | Channel 2 High-Side Logic Input (Table 1). INP2 has a 10k d pulldown resistor. |
| 25 | INC2 | Channel 2 Clamp Logic Input. Clamps OCP2 and OCN2 are turned on when INC2 is high and when INP2 and INN2 are low and SHDN and EN2 are high (Table 1). |
| 26 | INN2 | Channel 2 Low-Side Logic Input (Table 1). INN2 has a 10k pulldown resistor. |
| 27, 45 | $\mathrm{V}_{\mathrm{CC} 2}$ | Channel 2 Gate-Drive Supply-Voltage Input. Bypass $\mathrm{V}_{\mathrm{CC}}$ to GND with a $0.1 \mu \mathrm{~F}$ capacitor as close as possible to the device. |
| 29 | CDN2 | Channel 2 Low-Side Driver Output. Connect a 1nF to 10nF capacitor between CDN2 and CGN2 as close as possible to the device. |
| 30 | CGN2 | Channel 2 Low-Side Gate Input. Connect a 1nF to 10nF capacitor between CDN2 and CGN2 as close as possible to the device. |
| 31, 32 | $\mathrm{V}_{\text {NN2 }}$ | Channel 2 High-Side Negative Supply-Voltage Input. Bypass $\mathrm{V}_{\mathrm{NN} 2}$ to $\operatorname{GND}$ with a $0.1 \mu \mathrm{~F}$ capacitor as close as possible to the device. Depending on the output, additional bypassing may be required (see the Power Supplies and Bypassing section). |
| 34 | ON2 | Channel 2 Low-Side Drain Output |
| 35 | OCN2 | Channel 2 Low-Side Clamp Output |
| 37 | OCP2 | Channel 2 High-Side Clamp Ouput |
| 38 | OP2 | Channel 2 High-Side Drain Ouput |
| 40, 41 | $\mathrm{V}_{\text {PP2 }}$ | Channel 2 High-Side Positive Supply-Voltage Input. Bypass $\mathrm{V}_{\mathrm{PP} 2}$ to GND with a $0.1 \mu \mathrm{~F}$ capacitor as close as possible to the device. Depending on the pulser lead, additional bypassing may be required (see the Power Supplies and Bypassing section). |
| 42 | CGP2 | Channel 2 High-Side Gate Input. Connect a 1 nF to 10 nF capacitor between CDP2 and CGP2 as close as possible to the device. |
| 43 | CDP2 | Channel 2 High-Side Driver Output. Connect a 1 nF to 10 nF capacitor between CDP2 and CGP2 as close as possible to the device. |

## Dual, Unipolar/Bipolar, High-Voltage Digital Pulsers with Fault Condition Management

Pin Description (continued)

| PIN | NAME | FUNCTION |
| :---: | :---: | :---: |
| 46 | CGC2 | Channel 2 High-Side Clamp Gate Input. Connect a 1 nF to 10 nF capacitor between CDC2 and CGC2 as close as possible to the device. |
| 47 | CDC2 | Channel 2 High-Side Clamp Driver Output. Connect a 1 nF to 10 nF capacitor between CDC2 and CGC2 as close as possible to the device. |
| 48 | $\mathrm{V}_{\text {EE2 }}$ | Channel 2 Negative Supply Input. $\left\|V_{E E 2}\right\| \leq I V_{C C 2} I$. Gate-drive supply voltage for the OCP2 clamp. Bypass $\mathrm{V}_{\mathrm{EE} 2}$ to GND with a $0.1 \mu \mathrm{~F}$ capacitor as close as possible to the device. |
| 49 | $V_{D D}$ | Logic Supply-Voltage Input. Bypass $V_{D D}$ to GND with a $0.1 \mu \mathrm{~F}$ capacitor as close as possible to the device. Depending on the pulser lead, additional bypassing may be required (see the Power Supplies and Bypassing section). |
| 50 | $\mathrm{V}_{\text {SS }}$ | Substrate Voltage. Connect $\mathrm{V}_{\text {SS }}$ to a voltage equal to or more negative than the more negative of $\mathrm{V}_{\mathrm{NN} 1}$ or $\mathrm{V}_{\mathrm{NN} 2}$. Bypass $\mathrm{V}_{\mathrm{SS}}$ to GND with a $0.1 \mu \mathrm{~F}$ capacitor as close as possible to the device. |
| 51 | $\mathrm{V}_{\mathrm{EE} 1}$ | Channel 1 Negative Supply Input. IV $\mathrm{EE}^{1} \mid \leq \mathrm{IV}_{\mathrm{CC} 1}$ I. Gate-drive supply voltage for the OCP1 clamp. Bypass $\mathrm{V}_{\mathrm{EE} 1}$ to GND with a $0.1 \mu \mathrm{~F}$ capacitor as close as possible to the device. |
| 52 | CDC1 | Channel 1 High-Side Clamp Driver Output. Connect a 1 nF to 10 nF capacitor between CDC1 and CGC1 as close as possible to the device. |
| 53 | CGC1 | Channel 1 High-Side Clamp Gate Input. Connect a 1 nF to 10 nF capacitor between CDC1 and CGC1 as close as possible to the device. |
| 56 | CDP1 | Channel 1 High-Side Driver Output. Connect a 1 nF to 10 nF capacitor between CDP1 and CGP1 as close as possible to the device. |
| - | EP | Exposed Pad. EP must be connected to $V_{S S}$. Do not use EP as the only $V_{S S}$ connection for the device. |

# Dual, Unipolar/Bipolar, High-Voltage Digital Pulsers with Fault Condition Management 

## Detailed Description

The MAX14811 integrated circuit generates high-voltage, high-frequency unipolar or bipolar pulses from low-voltage logic inputs. The dual pulser features independent logic inputs, independent high-voltage pulser outputs with active clamps, and independent high-voltage supply inputs.

The device features fault condition management to protect the outputs. The outputs enter three-state if both $I N P$ _ and $I N N$ _ are logic-high. The device has a $9 \Omega$ output impedance for the high-voltage outputs and a $27 \Omega$ impedance for the active clamp. The high-voltage outputs are guaranteed to provide 2.0A (typ) output current. All the pulser outputs and clamp outputs have overvoltage protection.
The device uses three logic inputs per channel to control the positive and negative pulses and active clamp. Also included are two independent enable inputs. Disabling EN_ ensures the output MOSFETs are not
accidentally turned on during fast power-supply ramping. This allows for faster ramp times and shorter delays between pulsing modes. A low-power shutdown mode reduces power consumption to less than $1 \mu \mathrm{~A}$. All digital inputs are CMOS compatible.
Logic Inputs (INP_, INN_, INC_, EN_, $\overline{\mathbf{S H D N}}$ ) The device has a total of nine logic-input signals. SHDN controls the power-up and power-down of the device. There are two sets of INP_, INN_, INC_, and EN_ signals: one for each channel. Each INP_ and INN_ input has a $10 k \Omega$ (typ) pulldown resistor. INP_ controls the on and off states of the high-side FET, INN_ controls the on and off states of the low-side FET, INC_ controls the active clamp, and EN_ controls the gate-to-source short. These signals give complete control of the output stage of each driver (see Table 1 for all logic combinations).
The device logic inputs are CMOS-logic-compatible and the logic levels are referenced to $V_{D D}$ for maximum flexibility. The low 5pF (typ) input capacitance of the logic inputs reduces loading and increases switching speed.

Table 1. Truth Table

| INPUTS |  |  |  |  | OUTPUTS |  |  | STATE |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| $\overline{\text { SHDN }}$ | EN_ | INP_ | INN_ | INC_ | OP_ | ON_ | OCP_, OCN_ |  |
| 0 | X | X | X | X | High Impedance | High Impedance | High Impedance | Power-down, INP_/INN_ disabled, gate-source short disabled, clamp disabled. |
| 1 | 0 | X | X | X | High Impedance | High Impedance | High Impedance | Power-down, INP_IINN_ disabled, gate-source short enabled, clamp disabled. |
| 1 | 1 | 0 | 0 | 0 | High Impedance | High Impedance | High Impedance | Power-up, all inputs enabled, gatesource short disabled. |
| 1 | 1 | 0 | 0 | 1 | High Impedance | High Impedance | GND | Power-up, all inputs enabled, gatesource short disabled. |
| 1 | 1 | 0 | 1 | X | High Impedance | $\mathrm{V}_{\mathrm{NN}}$ | High Impedance | Power-up, all inputs enabled, gatesource short disabled. |
| 1 | 1 | 1 | 0 | X | $\mathrm{VPP}_{-}$ | High Impedance | High Impedance | Power-up, all inputs enabled, gatesource short disabled. |
| 1 | 1 | 1 | 1 | X | High Impedance | High Impedance | High Impedance | Fault condition if INP_ = 1 and INN_ = 1 for more than 5.5 ns . |

$X=$ Don't care, $0=$ Logic-low, $1=$ Logic-high .

# Dual, Unipolar/Bipolar, High-Voltage Digital Pulsers with Fault Condition Management 


#### Abstract

High-Voltage Output Protection The device's high-voltage outputs feature an integrated overvoltage protection circuit that allows the user to implement multilevel pulsing by connecting the outputs of multiple pulser channels in parallel. Internal diodes in series with the $O N_{-}$and $O P_{-}$outputs prevent the body diode of the high-side and low-side FETs from switching on when a voltage greater than $\mathrm{V}_{\mathrm{NN}}$ or $\mathrm{V}_{\mathrm{PP}}$ is present on the output. See the Functional Diagram.


## Active Clamps

The device features an active clamp circuit to improve pulse quality and reduce 2nd harmonic output. The clamp circuit consists of an n-channel (DC-coupled) and a p-channel (AC and DC delay coupled) high-voltage FETs that are switched on or off by the logic clamp input (INC_). The device features protected clamp devices, allowing the clamp circuit to be used in bipolar pulsing circuits (see the Functional Diagram and Figure 1). A diode in series with the OCN_ output prevents the body diode of the low-side FET from turning on when a voltage lower than GND is present. Another diode in series with the OCP_ output prevents the body diode of the highside FET from turning on when a voltage higher than ground is present.
The user can connect the active clamp input (INC_) to a logic-high voltage and drive only the INP_ and INN_ inputs to minimize the number of signals used to drive the device. In this case, whenever both the INP_ and INN_ inputs are low and the INC_ input is high, the active clamp circuit pulls the output to GND through the OCP_ and OCN_ outputs (see Table 1 for more information).

## Fault Protection

The device features fault protection management to protect the outputs. When INP_ and INN_ are both logichigh, the outputs ( $\mathrm{OP}_{-}, \mathrm{ON}_{-}, \mathrm{OCP}_{-}$, and OCN ) enter a high-Z state.

## Power-Supply Ramping and Gate-Source Short Circuit

The device includes a gate-source short circuit that is controlled by the enable input (EN_). When SHDN is high and $E N_{-}$is low, a $60 \Omega$ switch shorts together the gate and source of the high-side output FET. At the same time, a similar switch shorts the gate and source of the lowside output FET (Table 1). The gate-source short circuit prevents accidental turn-on of the output FETs due to the ramping voltage on $\mathrm{V}_{\mathrm{PP}}$ and $\mathrm{V}_{\mathrm{NN}}$, and allows for faster
ramping rates and smaller delay times between pulsing modes.

Shutdown Mode
$\overline{\text { SHDN }}$ is common to both channel 1 and channel 2 and powers up or down the device. Drive $\overline{\text { SHDN }}$ low to power down all internal circuits (except the clamp circuits). When SHDN is low, the device is in the lowest power state $(1 \mu \mathrm{~A})$ and the gate-source short circuit is disabled. The device takes $1 \mu \mathrm{~s}$ (typ) to become active when SHDN is disabled.

Thermal Protection
A thermal shutdown circuit with a typical threshold of $+150^{\circ} \mathrm{C}$ prevents damage due to excessive power dissipation. When the junction temperature exceeds $\mathrm{T}_{J}=+150^{\circ} \mathrm{C}$, all outputs are disabled. Normal operation typically resumes after the IC's junction temperature drops below $+130^{\circ} \mathrm{C}$.

## Applications Information

AC-Coupling Capacitor Selection The value of all AC-coupling capacitors (between CDP_ and CGP_ and between CDN_ and CGN_) must be between 1 nF and 10 nF . The voltage rating of the capacitor must be at least as high as VPP_. Place the capacitors as close as possible to the device. Because INP_ and part of INC_ are AC-coupled to the output devices, they cannot be driven high indefinitely when the device is active.

## Power Dissipation

The device's power dissipation consists of three major components caused by the current consumption from $V_{C C}, V_{P P}$, and $V_{N N_{1}}$. The sum of these components (PVCC_, PVPP ${ }_{-}$, and PVNN_) must be kept below the maximum power-dissipation limit. See the Typical Operating Characteristics section for more information on typical supply currents vs. switching frequencies. The device consumes most of the supply current from $V_{C C}$ supply to charge and discharge internal nodes such as the gate capacitance of the high-side FET ( $\mathrm{CP}_{\mathrm{P}}$ ) and the low-side FET $\left(\mathrm{C}_{\mathrm{N}}\right)$. Neglecting the small quiescent supply current and a small amount of current used to charge and discharge the capacitances at the internal gate clamp FETs, the power consumption can be estimated as follows:

$$
\begin{gathered}
\text { PVCC }_{-}=\left[\left(C_{N} \times V_{C C_{2}}^{2} \times f_{I N}\right)+\left(C_{P} \times V_{C_{-}}{ }^{2} \times f_{I N}\right)\right] \times \\
(B R F \times B T D)
\end{gathered}
$$

## Dual, Unipolar/Bipolar, High-Voltage Digital Pulsers with Fault Condition Management

$$
f_{I N}=f_{I N N_{-}}=f_{I N P_{-}}
$$

where $f_{I N N}$ and $f_{I N P}$ are the switching frequencies of the inputs $\overline{I N} N_{-}$and $\overline{I N} P_{-}$, respectively, and where BRF is the burst repetition frequency and BTD is the burst time duration. The typical value of the gate capacitances of the power FET are $\mathrm{C}_{\mathrm{N}}=0.2 \mathrm{nF}, \mathrm{CP}_{\mathrm{P}}=0.4 \mathrm{nF}$. For an output load that has a resistance of $R_{L}$ and capacitance of $C_{L}$, the power dissipation can be estimated as follows (assume square-wave output and neglect the resistance of the switches):
PVPP $_{-}=\left[\left(C_{O}+C_{L}\right) \times f_{I N} \times\left(\mathrm{V}_{\text {PP }}-\mathrm{V}_{\mathrm{NN}_{-}}\right)\right]^{2}+\left[\frac{\mathrm{V}_{\text {PP }}{ }_{-}{ }^{2}}{\mathrm{R}_{\mathrm{L}}} \times \frac{1}{2}\right] \times(\mathrm{BRF} \times \mathrm{BTD})$
where $\mathrm{C}_{\mathrm{O}}$ is the device's output capacitance.
Power Supplies and Bypassing
The device operates from independent supply voltage sets (only $\mathrm{V}_{\mathrm{DD}}$ and $\mathrm{V}_{\mathrm{SS}}$ are common to both channels). The logic input circuit operates from a +2.7 V to +6 V single supply ( $V_{D D}$ ). The level-shift driver dual supplies, $V_{C C} / V_{E E}$ operate from $\pm 4.75 \mathrm{~V}$ to $\pm 12.6 \mathrm{~V}$.
The $V_{P P} / N_{N N}$ _ high-side and low-side supplies are driven from a single positive supply up to +220 V , from a single negative supply up to -200 V , or from $\pm 110 \mathrm{~V}$ dual supplies. Either $\mathrm{V}_{\mathrm{PP}}$ _ or $\mathrm{V}_{\mathrm{NN}}$ _ can be set at OV . Bypass each supply input to ground with a $0.1 \mu \mathrm{~F}$ capacitor as close as possible to the device.
Depending on the load of the pulser, additional bypassing may be needed to keep the output of VPP_ and $\mathrm{V}_{\text {NN_ }}$ stable during output transitions. For example, with

COUT $=100$ pF and ROUT $=100 \Omega$ load, additional $10 \mu$ F (typ) capacitor is recommended. $\mathrm{V}_{\mathrm{SS}}$ is the substrate voltage and must be connected to a voltage equal to or more negative than the more negative voltage of $\mathrm{V}_{\mathrm{NN} 1}$ or $\mathrm{V}_{\mathrm{NN} 2}$.

Exposed Pad and Layout Concerns
The device provides an exposed pad (EP) underneath the TQFN package for improved thermal performance. The EP is internally connected to $\mathrm{V}_{\text {SS }}$. Connect EP to $V_{\text {SS }}$ externally and do not run traces under the package to avoid possible short circuits. To aid heat dissipation, connect EP to a similarly sized pad on the component side of the PCB. This pad should be connected through to the solder-side copper by several plated holes to a large heat-spreading copper area to conduct heat away from the device.
The device's high-speed pulser requires low-inductance bypass capacitors to their supply inputs. High-speed PCB trace design practices are recommended. Pay particular attention to minimize trace lengths and use sufficient trace width to reduce inductance. Use of surfacemount components is recommended.

## Supply Sequencing

$V_{\text {SS }}$ must be lower than or equal to the more negative voltage of $\mathrm{V}_{\mathrm{NN} 1}$ or $\mathrm{V}_{\mathrm{NN} 2}$ at all times. No other powersupply sequencing is required for the device.

## Typical Applications Circuit

Figure 7 shows the MAX14811 in a bipolar pulsing application.

MAX14811
Dual, Unipolar/Bipolar, High-Voltage Digital Pulsers with Fault Condition Management

Functional Diagram
 with Fault Condition Management


INC_ = HIGH

Figure 1. Detailed Timing ( $R_{L}=100 \Omega, C_{L}=100 \mathrm{pF}$ )


Figure 2. Enable Timing $\left(R_{L}=100 \Omega, C_{L}=100 \mathrm{pF}\right)$
$\qquad$


Figure 3. Active Clamp Timing ( $R_{L}=100 \Omega, C_{L}=100 \mathrm{pF}$ )


Figure 4. Short-Circuit Timing ( $R_{L}=100 \Omega, C_{L}=100 \mathrm{pF}$ )
$\qquad$


Figure 5. INP_ to INN_ Fault Overlap Detection Timing


Figure 6. Recovery from Fault Condition Timing with Fault Condition Management


Figure 7. Dual Bipolar Pulsing, $\pm 100 \mathrm{~V}$, GND

## Ordering Information

| PART | TEMP RANGE | PROTECTED OUTPUTS | OUTPUT CURRENT (A) | PIN-PACKAGE |
| :---: | :---: | :---: | :---: | :---: |
| MAX14811CTN + | $0^{\circ} \mathrm{C}$ to $+70^{\circ} \mathrm{C}$ | OCP $_{-}$, OCN_, OP_, ON_$^{2}$ | 2.0 | 56 TQFN-EP* |

+Denotes a lead(Pb)-free/RoHS-compliant package.
*EP = Exposed pad.
Warning: The MAX14811 is designed to operate with high voltages. Exercise caution.

## Package Information

For the latest package outline information and land patterns (footprints), go to www.maxim-ic.com/packages. Note that a "+", "\#", or "-" in the package code indicates RoHS status only. Package drawings may show a different suffix character, but the drawing pertains to the package regardless of RoHS status.

| PACKAGE TYPE | PACKAGE CODE | OUTLINE NO. | LAND PATTERN NO. |
| :---: | :---: | :---: | :---: |
| 56 TQFN-EP | $T 5677+1$ | $\underline{\mathbf{2 1 - 0 1 4 4}}$ | $\underline{90-0042}$ |

$\qquad$

| REVISION <br> NUMBER | REVISION <br> DATE | DESCRIPTION | PAGES <br> CHANGED |
| :---: | :---: | :---: | :---: |
| 0 | $12 / 10$ | Initial release | - |

